

Search Notes

Application/Control No.

10/823,229

Examiner

Chapman E. Jeanette

Applicant(s)/Patent under
Reexamination

TAKEUCHI ET AL.

Art Unit

3635

SEARCHED

Class	Subclass	Date	Examiner
52	167.1, 289, 650.1, 736.2		
	737.1		
	236.6		
	655.1		
	714		
403	403,262		
	187,174		
	408.1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR